The Automatic Radio Frequency Techniques Group (ARFTG) is a technical organization interested in all aspects of RF and microwave test and measurement. ARFTG was originally set up in 1972 to help the end user get the most from the latest generation test and measurement equipment. As the high-frequency measurement field has continued to evolve, so has ARFTG, which now has more than 600 members worldwide. ARFTG’s core mission is one of education, and it achieves this by hosting conferences, workshops, and training courses covering a wide range of topics in RF, microwave, and mm-wave measurement, but also by handing out student fellowships.

Moreover, ARFTG’s close association with the top vendors of measurement instrumentation ensures excellent equipment exhibits. Vendors often choose to launch their new product ranges during these exhibits. The extended break-outs from conference technical sessions enable excellent interactions to take place among colleagues, experts, and vendors.

ARFTG sponsors two meetings each year—one in the spring and one in the fall. Events that take place at these meetings are described here.

**Spring**

During the Microwave Theory and Techniques Society (MTT-S) Microwave Week, the following will take place:

• a one-day microwave measurement conference on Friday
• two workshops cosponsored with the International Microwave Symposium (IMS)
• an NVNA users forum
• vendor exhibition.

**Fall**

A four-day symposium will feature the following:

• a one-and-a-half day microwave measurement conference
• a one-and-a-half day microwave measurement training course
• two workshops on specific topics (e.g., nonlinear measurement, signal integrity, RF power amplifier design, and millimeter-wave measurement)
• an NVNA users forum
• vendor exhibition.

**ARFTG at Microwave Week 2012**

ARFTG is an integral part of MTT-S Microwave Week in Montréal and will take place on the last day of that week (Friday, 22 June). The venue will be the Palais des Congrès de Montréal. So if you are at all interested in measurements, particularly high-frequency measurements (anything from 1 kHz to 1 THz), plan on attending. You’ll find the atmosphere informal and friendly.

Chances are that you will take away much more than what you came with, perhaps some fresh ideas to help with your current projects and some new technical contacts.

Oral technical sessions at ARFTG conferences (Figure 1) are conducted in a single-track style, with papers on topical subjects that are both theoretical and practical, address the user and the

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**Dominique Schreurs, Jean-Pierre Teyssier, Nick Ridler, and Mohamed Sayed**

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**Figure 1. Oral technical session at the 77th ARFTG Conference in Baltimore, Maryland.**
manufacturer, and cover both modeling and measurement. Next to oral presentations, authors may present their work in the open forum that runs jointly with the vendor exhibition (Figure 2).

The theme of this year’s conference is “Nonlinear Measurement Systems.” In particular, papers were solicited in areas including:

- nonlinear measurement techniques in time domain and envelope domain
- nonlinear measurement systems calibration and verification issues
- nonlinear RF devices modeling
- measurement system/instrumentation design issues and methodologies
- on-wafer and fixtured high power measurements.

Contributions in other areas of RF, microwave, and/or millimeter wave measurement were also welcomed.

The most stimulating part of the ARFTG experience is the opportunity to interact one on one with colleagues, experts, and vendors in the RF and microwave test and measurement community. The somewhat more open conference schedule and the presence of many knowledgeable people in the high frequency measurement field make it more possible to get questions answered and to learn new material.

Need to Know More?
The ARFTG’s Web site (www.arftg.org) usually has all you need to know about upcoming events. This includes our conference during Microwave Week 2012. Alternatively, there are some key contacts within the ARFTG organizing group as follows:

- for sponsorship information, contact Joe Gering at sponsorship@arftg.org
- for exhibits information, contact Rusty Myers at exhibits@arftg.org
- for NVNA users’ forum information, contact Patrick Roblin at nvna_usersforum@arftg.org
- for conference technical program information, contact Jean-Pierre Teyssier at j-pierre.teyssier@brive.unilim.fr
- for all other conference matters, contact Dominique Schreurs at dominique.schreurs@ieee.org.

Figure 2. Open forum and exhibition at the 77th ARFTG Conference in Baltimore, Maryland.

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